

Search Notes



Application/Control No.

10/782,756

Examiner

Tran N. Nguyen

Applicant(s)/Patent under Reexamination

YAMADA ET AL.

Art Unit

2834

SEARCHED

Class	Subclass	Date	Examiner
310	216 ↓ 218	7/26/05	TNN
310	194	7/27/05	TNN
310	254 261 267 268	7/28/05	TNN
336	234 233 212		
(with bobbin spool)			

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR